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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No. : 10/689,314
Applicant : David Berman, et al.
Filing Date : October 20, 2003
For : X-RAY REFLECTOMETRY OF
THIN FILM LAYERS WITH
ENHANCED ACCURACY
Art Unit : 2882
Docket No. : 22350/21

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Date of Deposit: August 29, 2005	
I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail" service under 37 CFR 1.10 on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.	
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Signature: 	

STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

On March 5, 2004, a Response to Notice to File Missing Parts was filed in the U.S. Patent and Trademark Office. Subsequently, Information Disclosure Statements were filed on June 25, 2004 and December 20, 2004.

To date, we have received no Office Action for the above-referenced patent application. We inquire as to the status of the application and when we can expect to receive the first Office Action.

Respectfully submitted,

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Dated: New York, New York
August 29, 2005